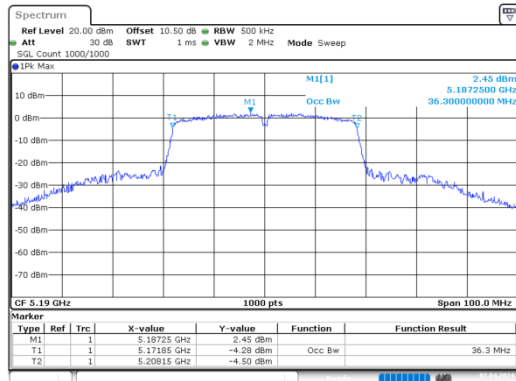
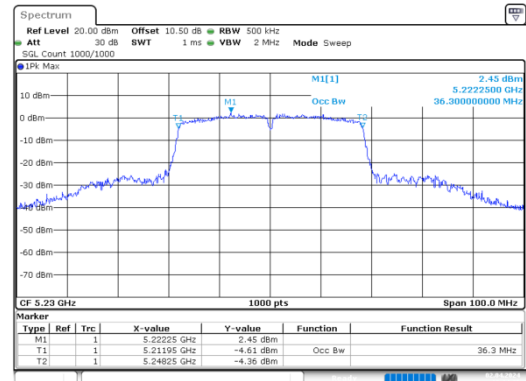


n40_5190MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:14:10

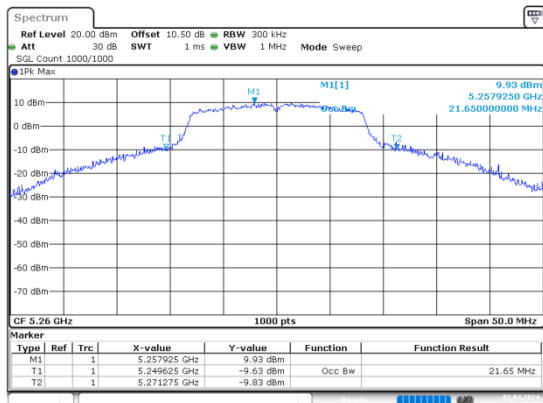
n40_5230MHz_Chain 0



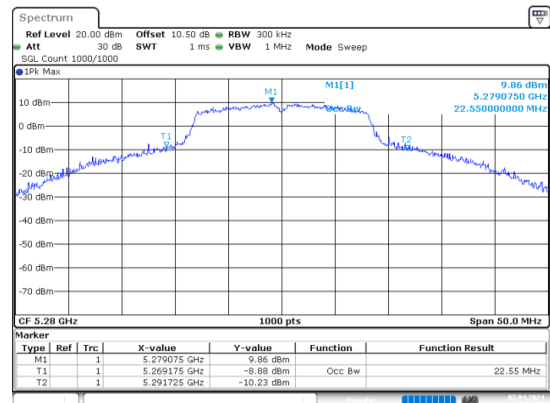
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:14:35

5250-5350MHz:

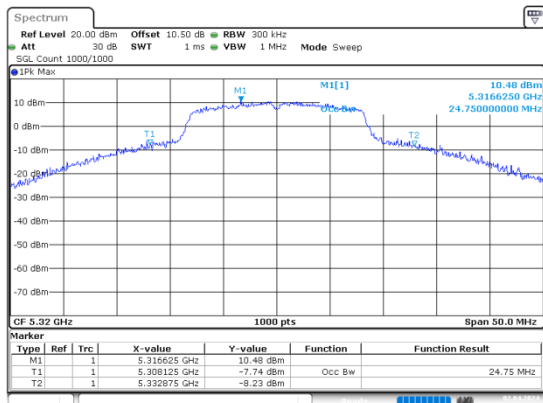
a_5260MHz_Chain 0



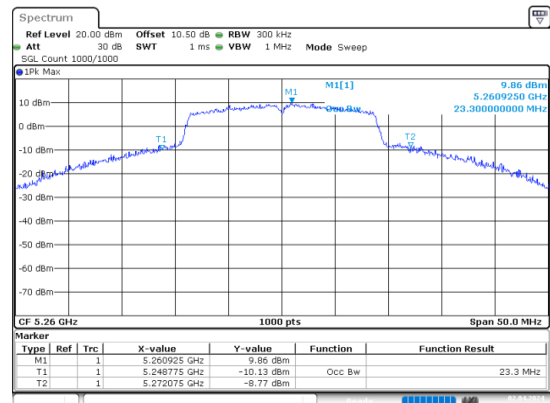
a_5280MHz_Chain 0



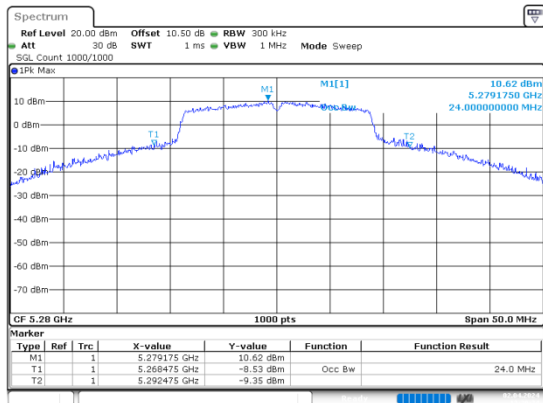
a_5320MHz_Chain 0



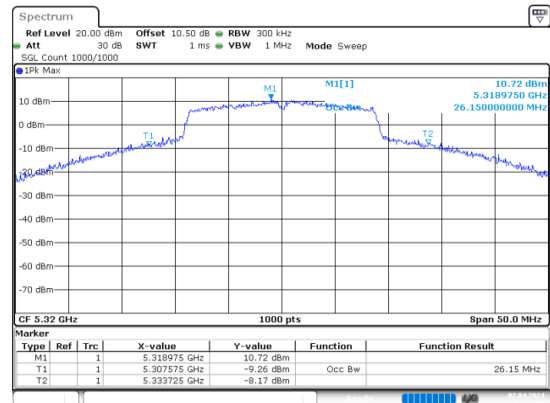
n20_5260MHz_Chain 0



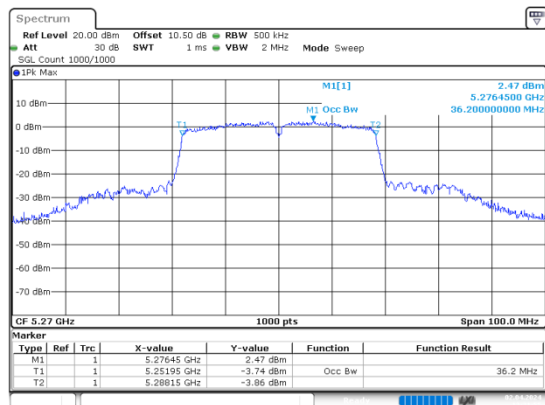
n20_5280MHz_Chain 0



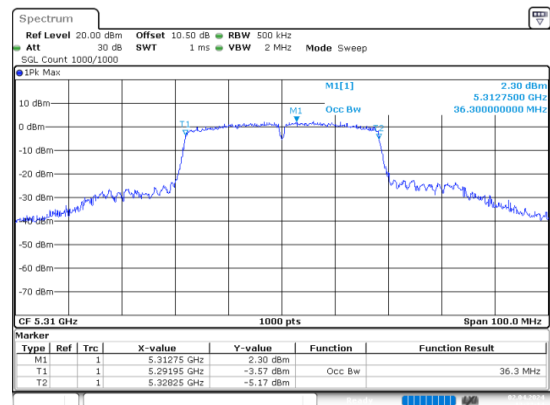
n20_5320MHz_Chain 0



n40_5270MHz_Chain 0

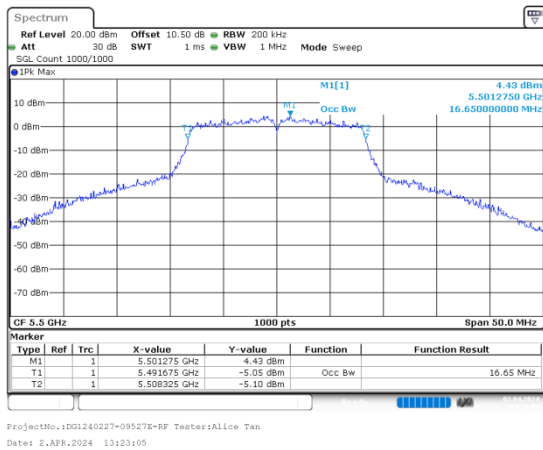


n40_5310MHz_Chain 0

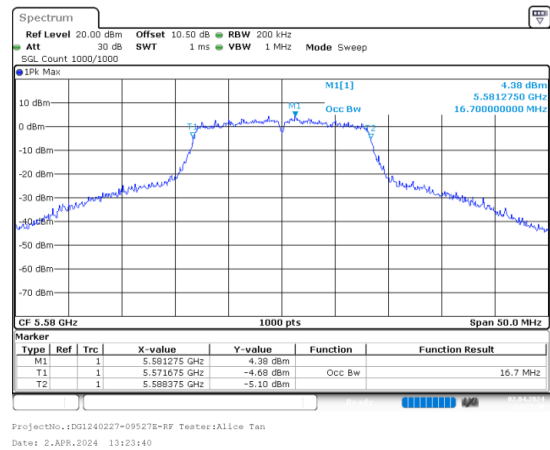


5470-5725MHz:

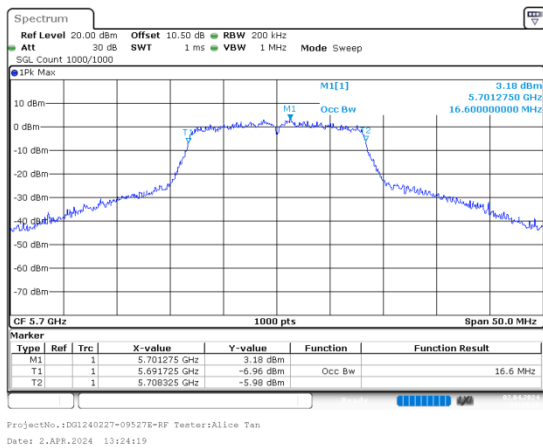
a_5500MHz_Chain 0



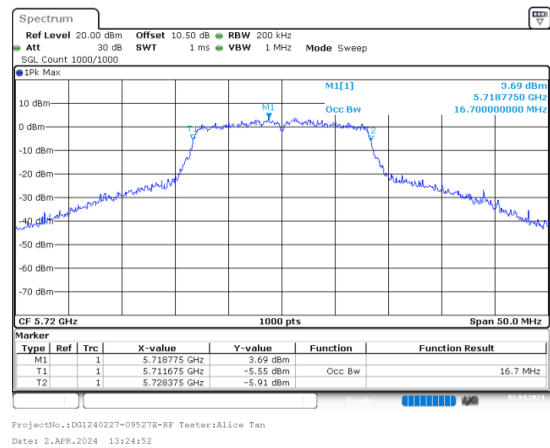
a_5580MHz_Chain 0



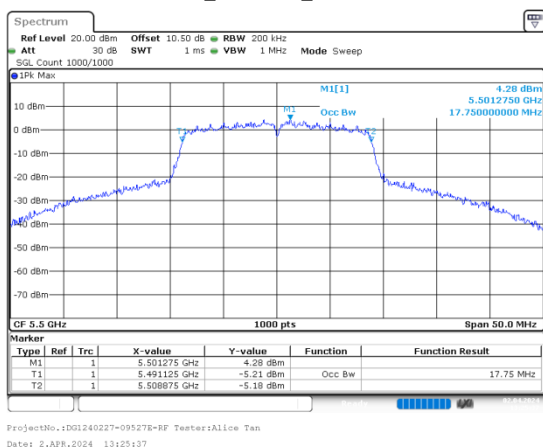
a_5700MHz_Chain 0



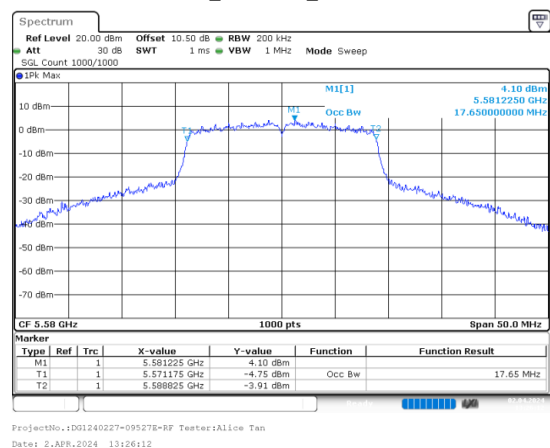
a_5720MHz_Chain 0



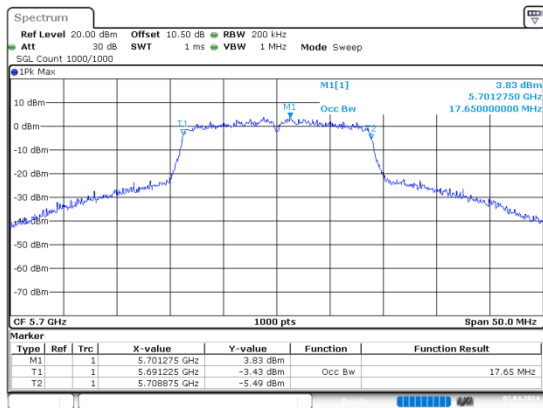
n20_5500MHz_Chain 0



n20_5580MHz_Chain 0

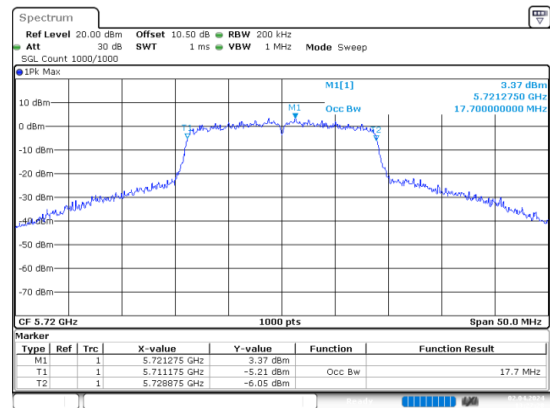


n20_5700MHz_Chain 0



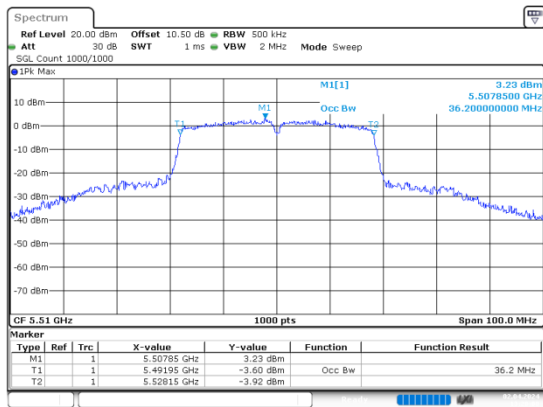
ProjectNo.:DG1240227-09527E-RF Testers: Alice Tan
Date: 2.APR.2024 13:26:52

n20_5720MHz_Chain 0



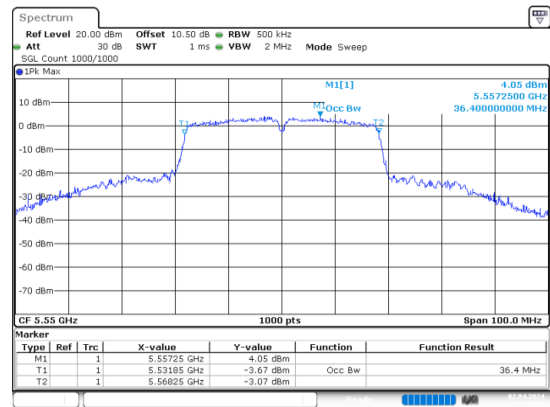
ProjectNo.:DG1240227-09527E-RF Testers: Alice Tan
Date: 2.APR.2024 13:27:28

n40_5510MHz_Chain 0



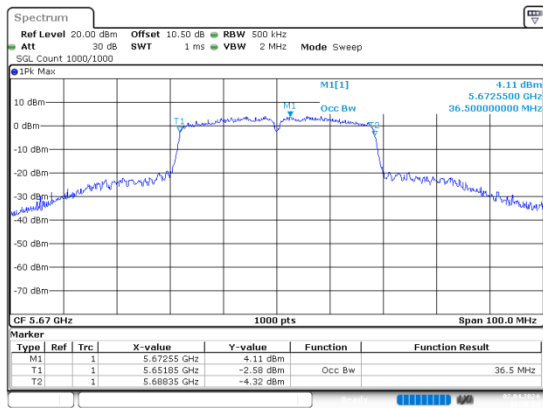
ProjectNo.:DG1240227-09527E-RF Testers: Alice Tan
Date: 2.APR.2024 13:28:00

n40_5550MHz_Chain 0



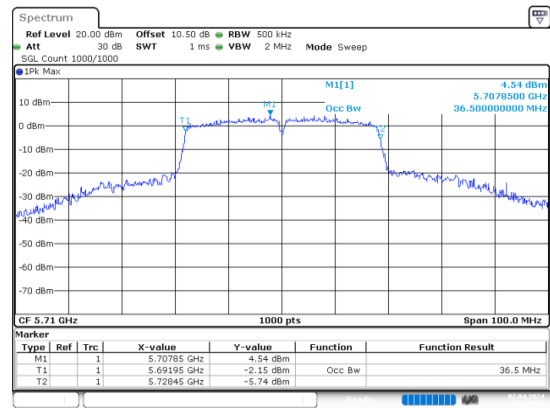
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Date: 2.APR.2024 13:28:12

n40_5670MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Testers: Alice Tan
Date: 2.APR.2024 13:28:54

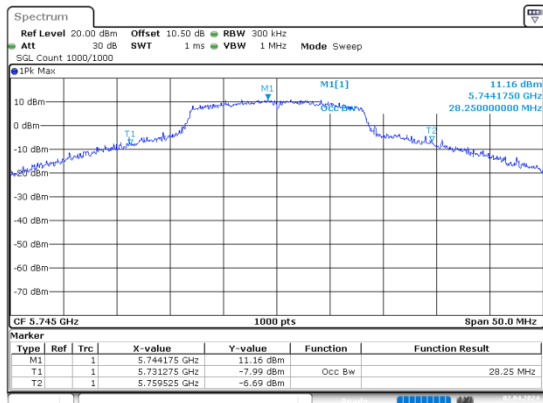
n40_5710MHz_Chain 0



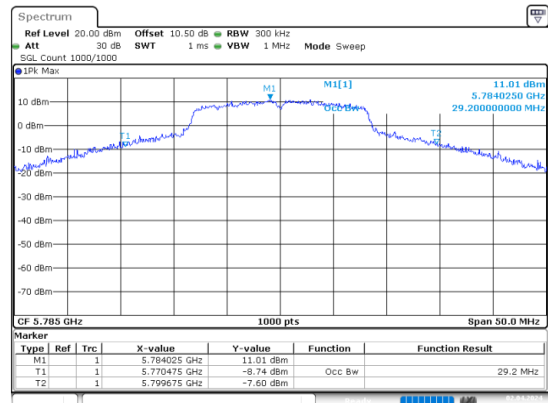
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Date: 2.APR.2024 13:29:23

5725-5850MHz:

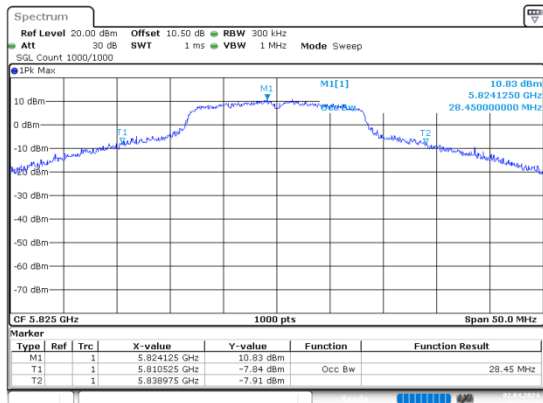
a_ 5745 MHz_Chain 0



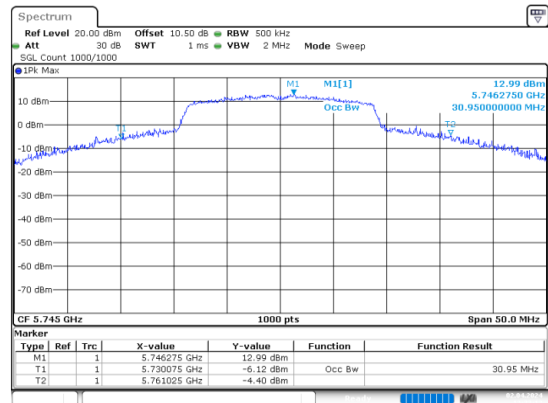
a_ 5785MHz_Chain 0



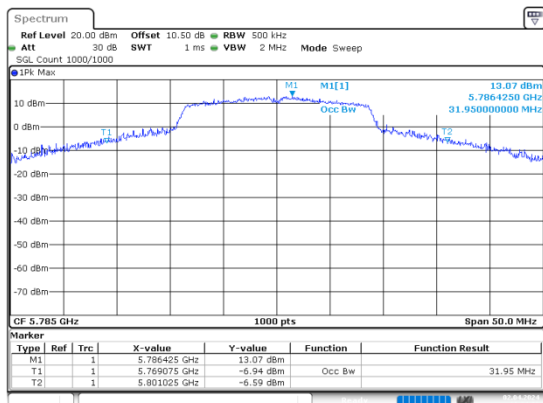
a_ 5825MHz_Chain 0



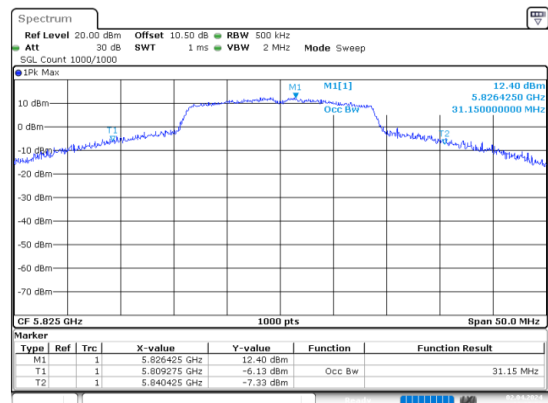
n20_ 5745MHz_Chain 0



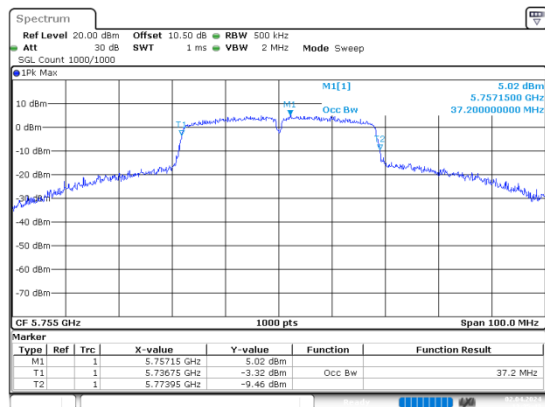
n20_ 5785MHz_Chain 0



n20_ 5825MHz_Chain 0

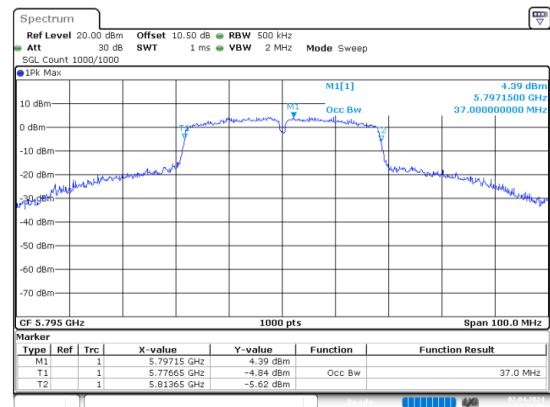


n40_5755MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:35:43

n40_5795MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:36:08

5.5 Maximum Conducted Output Power

Serial No.:	2I25-7	Test Date:	2024/4/2
Test Site:	RF	Test Mode:	Transmitting
Tester:	Alice Tan	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.3	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Anritsu	Microwave Peak Power Sensor	MA24418A	12618	2023/09/04	2024/09/03
Eastsheep	Coaxial Attenuator	5W-N-JK-6G-10dB	F-08-EM503	2023/09/10	2024/09/09

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Test Data:**5150-5250 MHz:**

Mode	Average Conducted Output Power (dBm)	Limit (dBm)	Result
a_5180MHz_Chain 0	18.02	24	Pass
a_5200MHz_Chain 0	17.94	24	Pass
a_5240MHz_Chain 0	18.25	24	Pass
n20_5180MHz_Chain 0	17.87	24	Pass
n20_5200MHz_Chain 0	17.93	24	Pass
n20_5240MHz_Chain 0	18.22	24	Pass
n40_5190MHz_Chain 0	14.42	24	Pass
n40_5230MHz_Chain 0	14.76	24	Pass

5250-5350 MHz:

Mode	Average Conducted Output Power (dBm)	Limit (dBm)	Result
a_5260MHz_Chain 0	18.49	24	Pass
a_5280MHz_Chain 0	18.82	24	Pass
a_5320MHz_Chain 0	19.34	24	Pass
n20_5260MHz_Chain 0	18.48	24	Pass
n20_5280MHz_Chain 0	18.8	24	Pass
n20_5320MHz_Chain 0	19.32	24	Pass
n40_5270MHz_Chain 0	13.58	24	Pass
n40_5310MHz_Chain 0	13.55	24	Pass

5470-5725 MHz:

Mode	Average Conducted Output Power (dBm)	Limit (dBm)	Result
a_5500MHz_Chain 0	14.62	24	Pass
a_5580MHz_Chain 0	14.37	24	Pass
a_5700MHz_Chain 0	13.95	24	Pass
a_5720MHz_Chain 0	13.91	24	Pass
n20_5500MHz_Chain 0	14.74	24	Pass
n20_5580MHz_Chain 0	14.5	24	Pass
n20_5700MHz_Chain 0	13.73	24	Pass
n20_5720MHz_Chain 0	13.84	24	Pass
n40_5510MHz_Chain 0	12.82	24	Pass
n40_5550MHz_Chain 0	13.66	24	Pass
n40_5670MHz_Chain 0	13.94	24	Pass
n40_5710MHz_Chain 0	13.91	24	Pass

5725-5850 MHz

Mode	Average Conducted Output Power (dBm)	Limit (dBm)	Result
a_5745MHz_Chain 0	20.05	30	Pass
a_5785MHz_Chain 0	19.72	30	Pass
a_5825MHz_Chain 0	19.22	30	Pass
n20_5745MHz_Chain 0	19.96	30	Pass
n20_5785MHz_Chain 0	19.7	30	Pass
n20_5825MHz_Chain 0	19.18	30	Pass
n40_5755MHz_Chain 0	15.82	30	Pass
n40_5795MHz_Chain 0	15.51	30	Pass

5.6 Maximum power spectral density

Serial No.:	2I25-7	Test Date:	2024/4/2
Test Site:	RF	Test Mode:	Transmitting
Tester:	Alice Tan	Test Result:	Pass

Environmental Conditions:

Temperature: (°C)	27.3	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
R&S	Spectrum Analyzer	FSV40	101589	2023/10/18	2024/10/17
Eastsheep	Coaxial Attenuator	5W-N-JK-6G-10dB	F-08-EM503	2023/09/10	2024/09/09

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Test Data:

5150-5250 MHz:

Mode	Value (dBm/MHz)	Duty Cycle Factor (dB)	PSD (dBm/MHz)	Limit (dBm/MHz)	Result
a_5180MHz_Chain 0	5.49	0.1	5.59	11.00	Pass
a_5200MHz_Chain 0	6.45	0.1	6.55	11.00	Pass
a_5240MHz_Chain 0	7.13	0.1	7.23	11.00	Pass
n20_5180MHz_Chain 0	6.19	0.11	6.3	11.00	Pass
n20_5200MHz_Chain 0	6.25	0.11	6.36	11.00	Pass
n20_5240MHz_Chain 0	6.96	0.11	7.07	11.00	Pass
n40_5190MHz_Chain 0	-2.56	0.22	-2.34	11.00	Pass
n40_5230MHz_Chain 0	-2.30	0.22	-2.08	11.00	Pass

5250-5350 MHz:

Mode	Value (dBm/MHz)	Duty Cycle Factor (dB)	PSD (dBm/MHz)	Limit (dBm/MHz)	Result
a_5260MHz_Chain 0	7.47	0.1	7.57	11.00	Pass
a_5280MHz_Chain 0	8.05	0.1	8.15	11.00	Pass
a_5320MHz_Chain 0	8.47	0.1	8.57	11.00	Pass
n20_5260MHz_Chain 0	7.18	0.11	7.29	11.00	Pass
n20_5280MHz_Chain 0	7.60	0.11	7.71	11.00	Pass
n20_5320MHz_Chain 0	8.07	0.11	8.18	11.00	Pass
n40_5270MHz_Chain 0	-2.11	0.22	-1.89	11.00	Pass
n40_5310MHz_Chain 0	-1.47	0.22	-1.25	11.00	Pass

5470-5725 MHz:

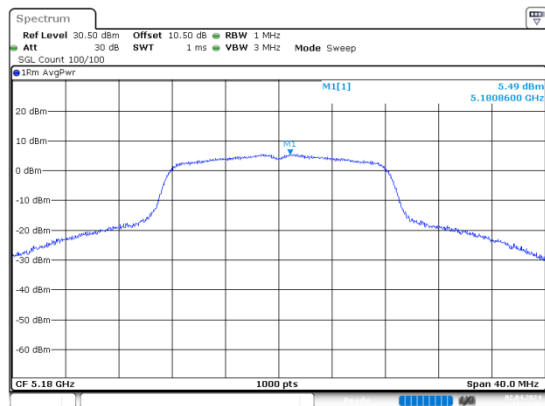
Mode	Value (dBm/MHz)	Duty Cycle Factor (dB)	PSD (dBm/MHz)	Limit (dBm/MHz)	Result
a_5500MHz_Chain 0	3.79	0.1	3.89	11.00	Pass
a_5580MHz_Chain 0	3.72	0.1	3.82	11.00	Pass
a_5700MHz_Chain 0	2.43	0.1	2.53	11.00	Pass
a_5720MHz_Chain 0	2.30	0.1	2.4	11.00	Pass
n20_5500MHz_Chain 0	3.38	0.11	3.49	11.00	Pass
n20_5580MHz_Chain 0	3.59	0.11	3.7	11.00	Pass
n20_5700MHz_Chain 0	2.73	0.11	2.84	11.00	Pass
n20_5720MHz_Chain 0	2.14	0.11	2.25	11.00	Pass
n40_5510MHz_Chain 0	-2.12	0.22	-1.9	11.00	Pass
n40_5550MHz_Chain 0	-1.33	0.22	-1.11	11.00	Pass
n40_5670MHz_Chain 0	-1.25	0.22	-1.03	11.00	Pass
n40_5710MHz_Chain 0	-0.66	0.22	-0.44	11.00	Pass

5725-5850 MHz

Mode	Value (dBm/500kHz)	Duty Cycle Factor (dB)	PSD (dBm/500kHz)	Limit (dBm/500kHz)	Result
a_5745MHz_Chain 0	5.93	0.1	6.03	30.00	Pass
a_5785MHz_Chain 0	6.14	0.1	6.24	30.00	Pass
a_5825MHz_Chain 0	5.47	0.1	5.57	30.00	Pass
n20_5745MHz_Chain 0	5.78	0.11	5.89	30.00	Pass
n20_5785MHz_Chain 0	5.90	0.11	6.01	30.00	Pass
n20_5825MHz_Chain 0	5.21	0.11	5.32	30.00	Pass
n40_5755MHz_Chain 0	-3.34	0.22	-3.12	30.00	Pass
n40_5795MHz_Chain 0	-3.48	0.22	-3.26	30.00	Pass

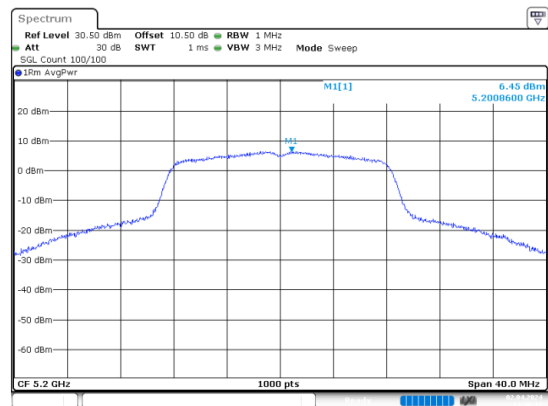
5150-5250 MHz:

a_ 5180 MHz_Chain 0



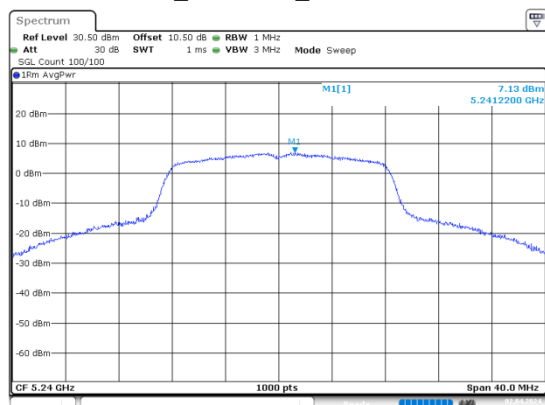
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:37:48

a_5200MHz_Chain 0



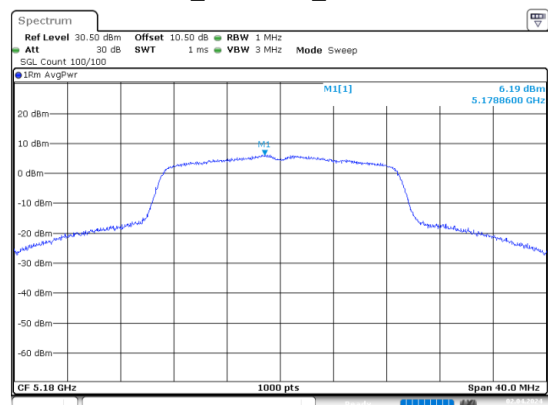
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:38:17

a_5240MHz_Chain 0



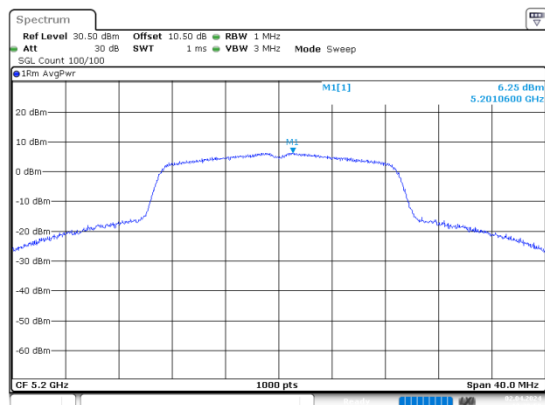
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:38:51

n20_5180MHz_Chain 0



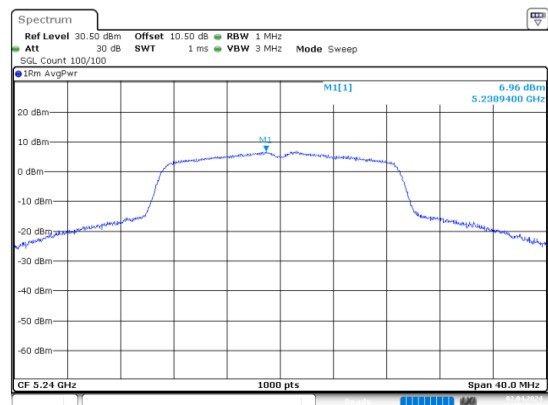
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Date: 2.APR.2024 13:39:37

n20_5200MHz_Chain 0



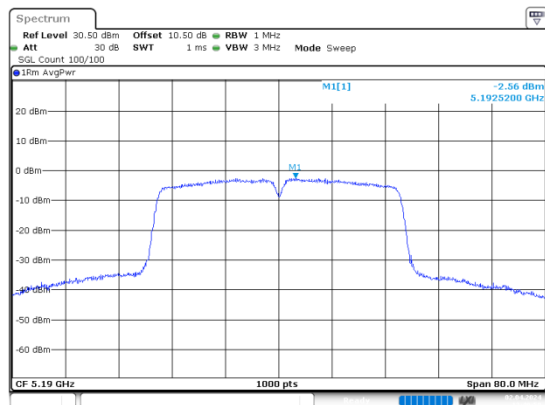
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:39:59

n20_5240MHz_Chain 0



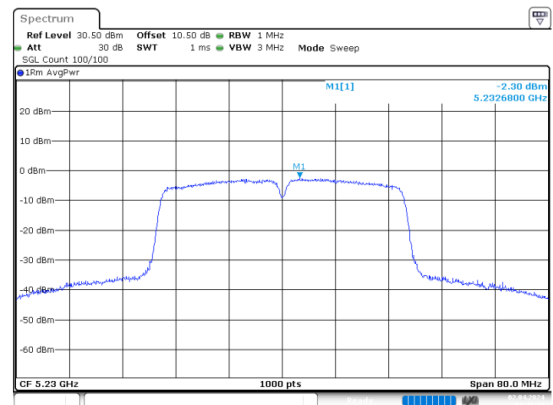
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:40:23

n40_5190MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:40:59

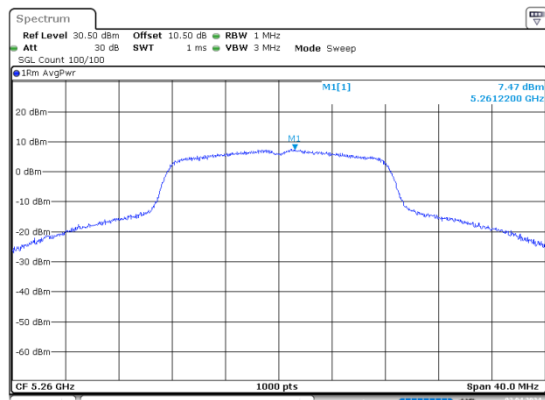
n40_5230MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:41:22

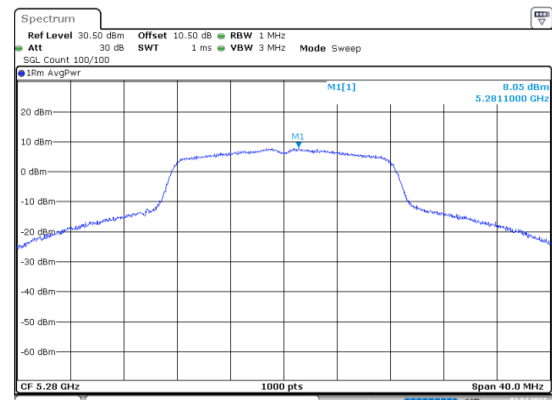
5250-5350 MHz:

a_5260MHz_Chain 0



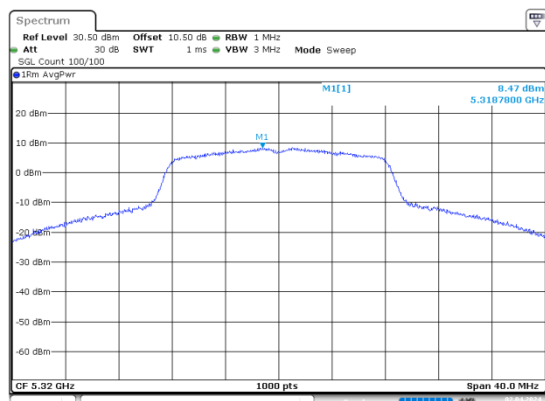
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:42:03

a_5280MHz_Chain 0



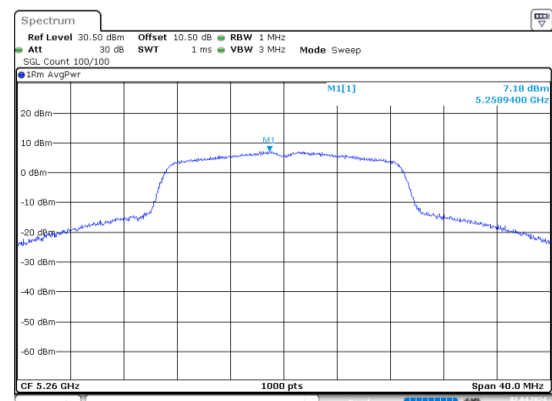
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:42:46

a_5320MHz_Chain 0



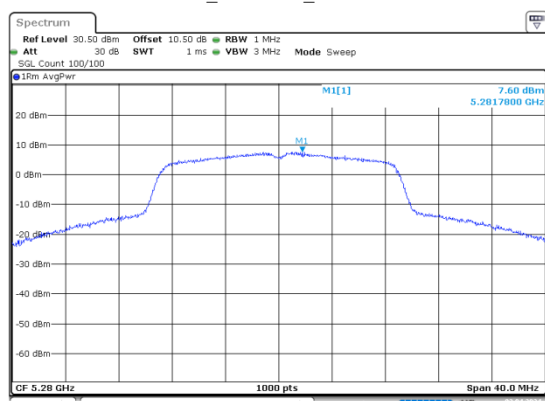
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Date: 2.APR.2024 13:43:13

n20_5260MHz_Chain 0



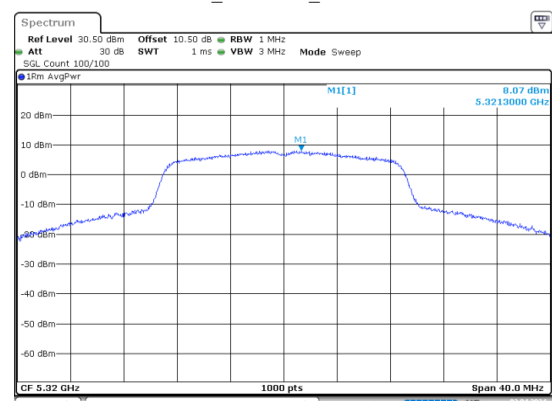
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Date: 2.APR.2024 13:43:45

n20_5280MHz_Chain 0



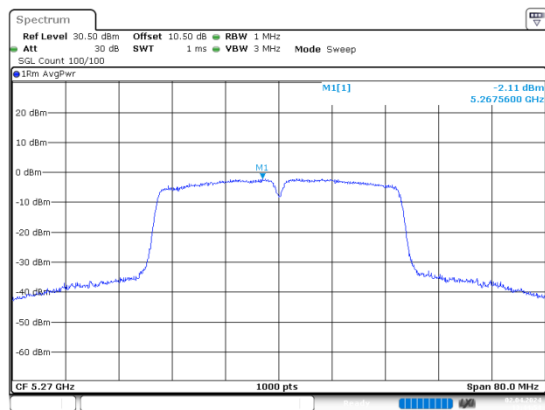
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:44:08

n20_5320MHz_Chain 0



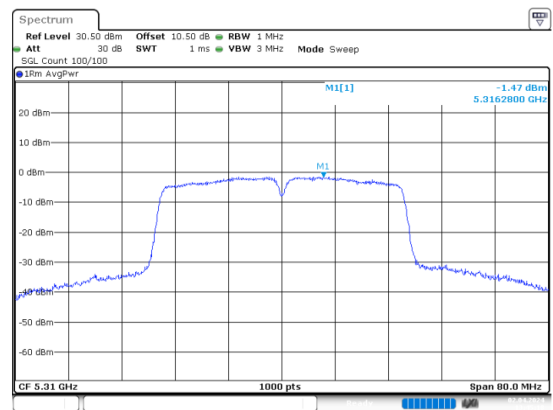
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:44:33

n40_5270MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Testert:Alice Tan
Date: 2.APR.2024 13:44:55

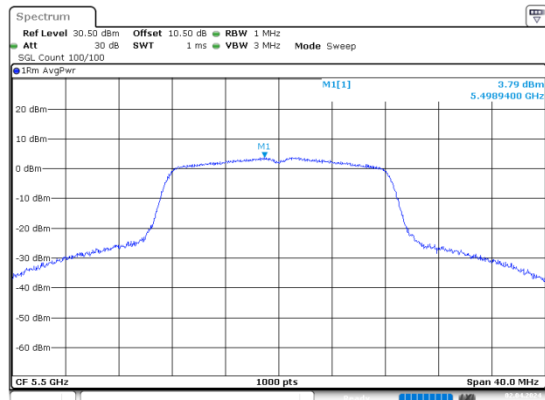
n40_5310MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Testert:Alice Tan
Date: 2.APR.2024 13:45:18

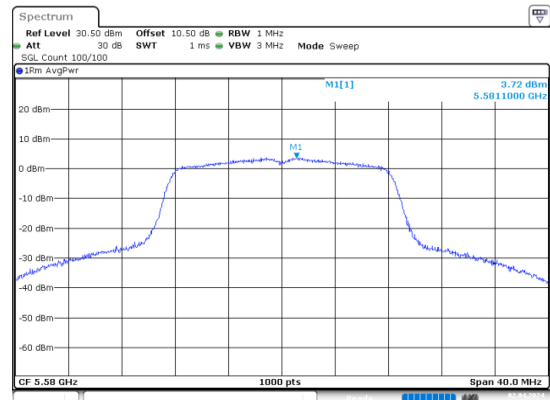
5470-5725 MHz:

a_5500MHz_Chain 0



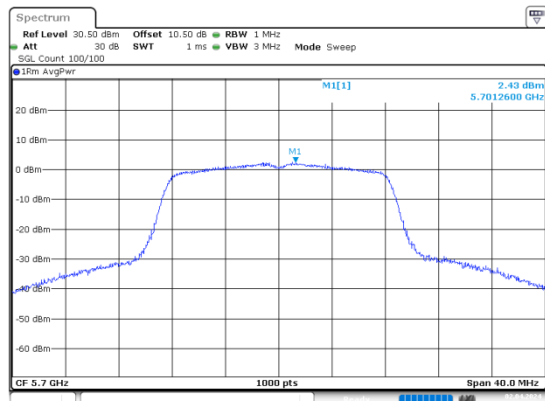
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:45:57

a_5580MHz_Chain 0



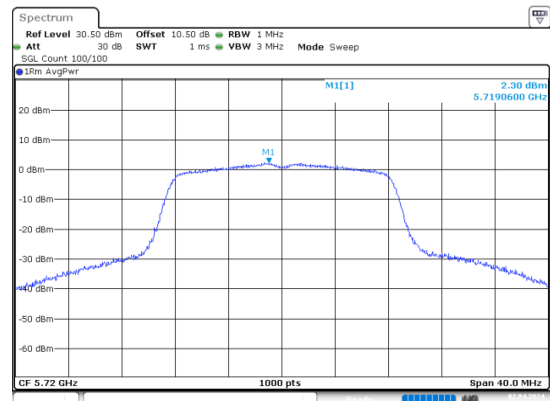
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:46:23

a_5700MHz_Chain 0



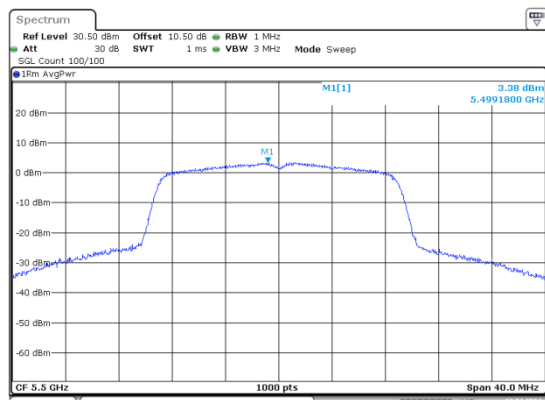
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:46:51

a_5720MHz_Chain 0



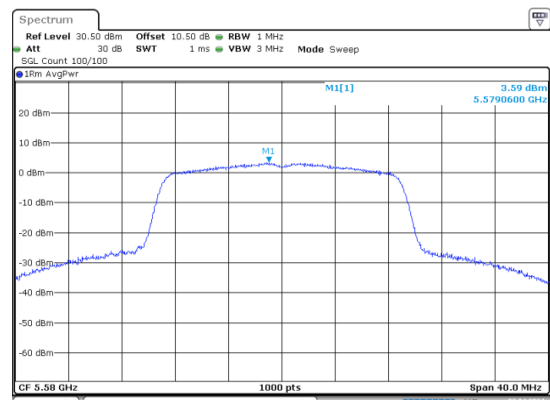
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:47:09

n20_5500MHz_Chain 0



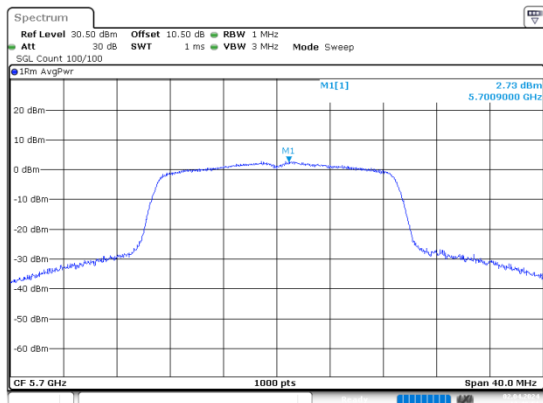
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:47:41

n20_5580MHz_Chain 0



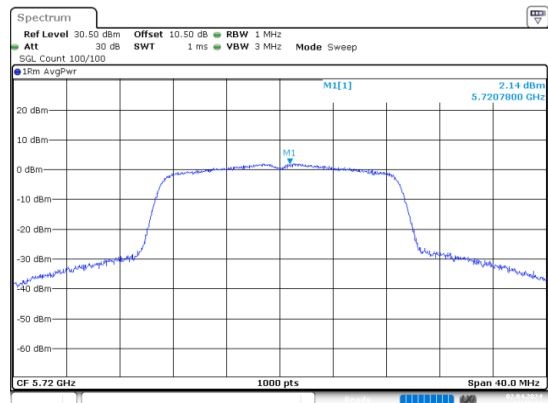
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:48:05

n20_5700MHz_Chain 0



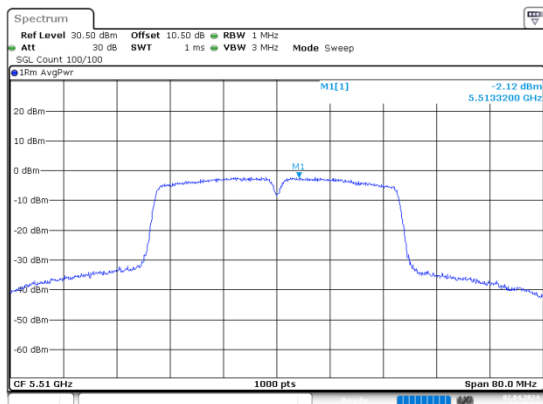
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:48:51

n20_5720MHz_Chain 0



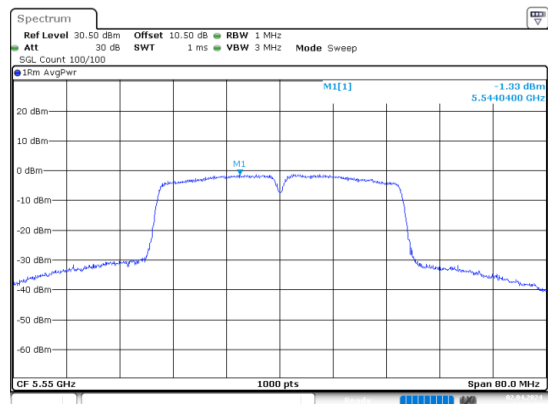
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:49:17

n40_5510MHz_Chain 0



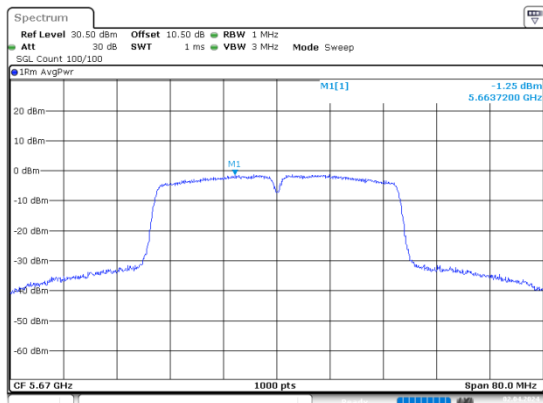
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:49:54

n40_5550MHz_Chain 0



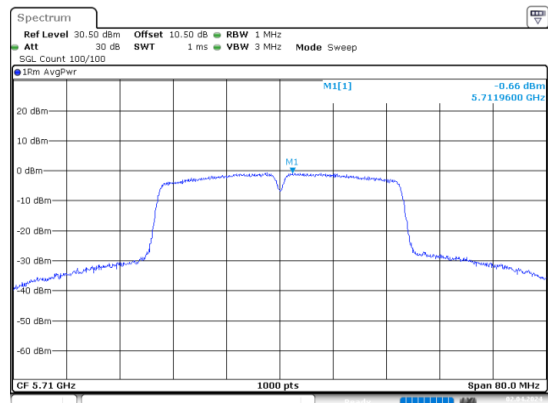
ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 14:35:00

n40_5670MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:50:48

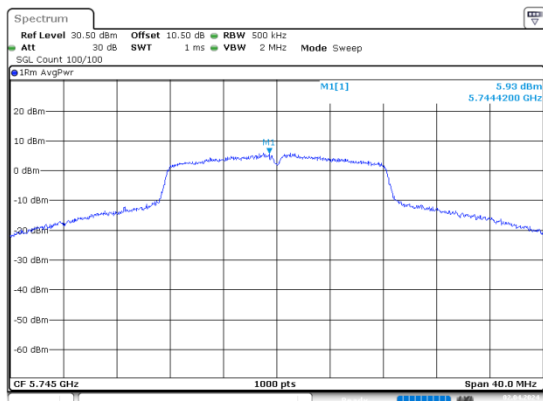
n40_5710MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester: Alice Tan
Date: 2.APR.2024 13:51:14

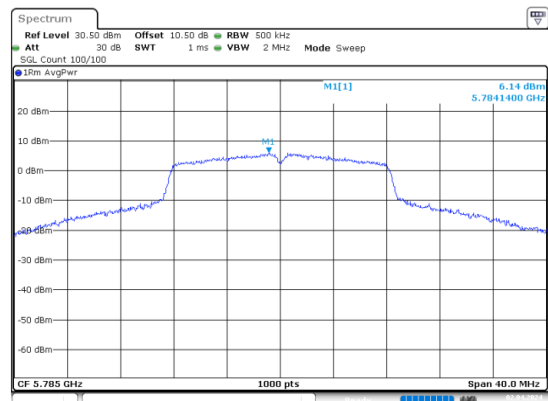
5725-5850 MHz:

a_5745 MHz_Chain 0



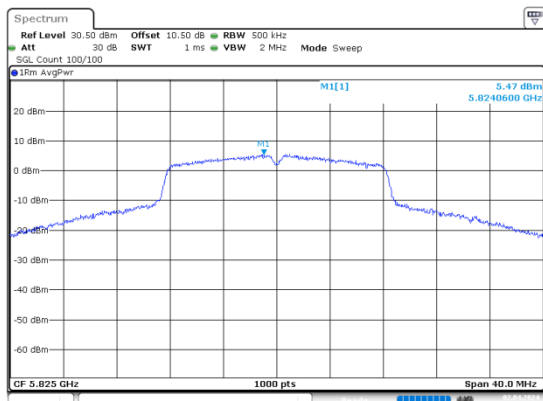
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:53:23

a_5785MHz_Chain 0



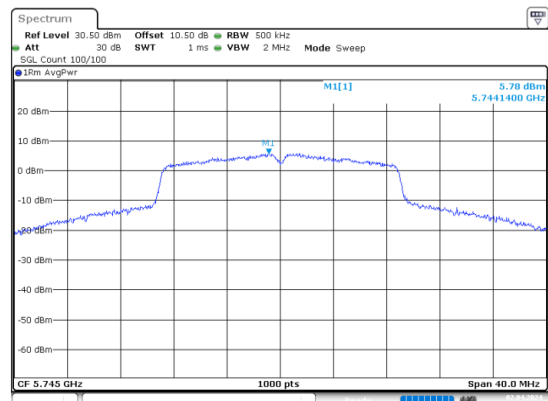
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:53:49

a_5825MHz_Chain 0



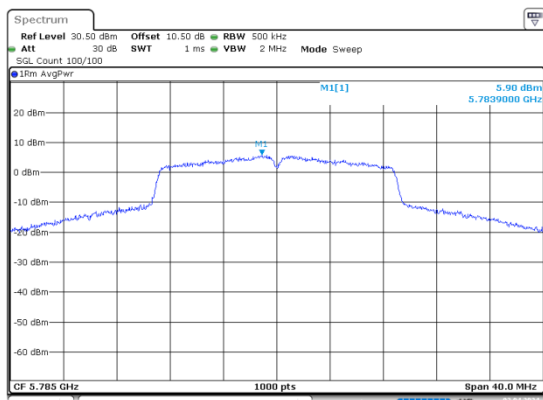
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:54:11

n20_5745MHz_Chain 0



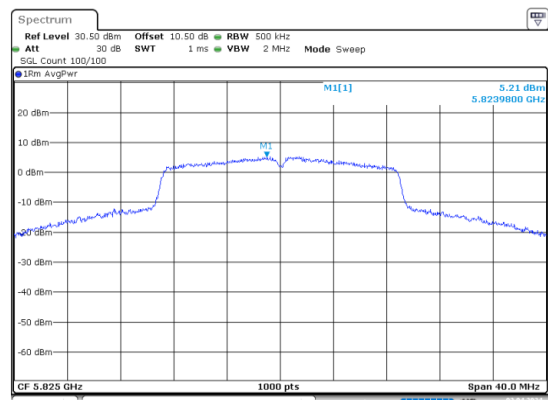
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:55:08

n20_5785MHz_Chain 0



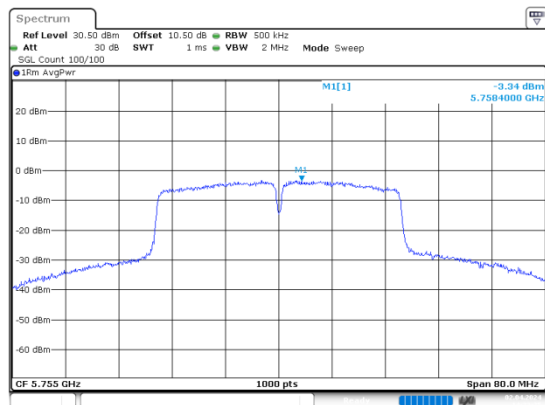
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:56:04

n20_5825MHz_Chain 0



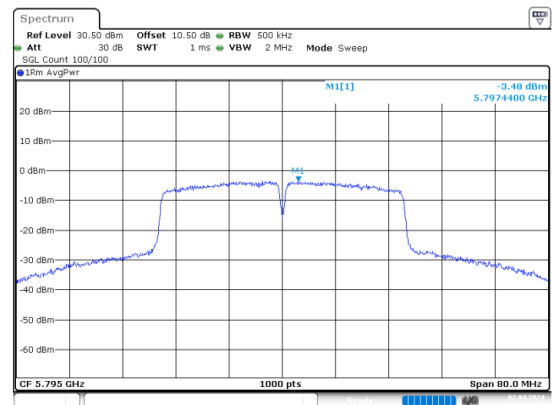
ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 13:56:44

n40_5755MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 14:33:36

n40_5795MHz_Chain 0



ProjectNo.:DG1240227-09527E-RF Tester:Alice Tan
Date: 2.APR.2024 14:31:55

5.7 Duty Cycle

Serial No.:	2I25-7	Test Date:	2024/4/2
Test Site:	RF	Test Mode:	Transmitting
Tester:	Alice Tan	Test Result:	/

Environmental Conditions:

Temperature: (°C)	27.3	Relative Humidity: (%)	53	ATM Pressure: (kPa)	100.2
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Test Equipment List and Details:

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
R&S	Spectrum Analyzer	FSV40	101589	2023/10/18	2024/10/17
Eastsheep	Coaxial Attenuator	5W-N-JK-6G-10dB	F-08-EM503	2023/09/10	2024/09/09

* Statement of Traceability: Bay Area Compliance Laboratories Corp. (Dongguan) attests that all calibrations have been performed, traceable to National Primary Standards and International System of Units (SI).

Test Data:**5150-5250 MHz:**

Test Modes	Ton (ms)	Ton+off (ms)	Duty cycle (%)	1/T (Hz)	Duty cycle Factor (dB)	VBW Setting (kHz)
a_Chain 0	1.396	1.428	97.76	716	0.10	1
n20_Chain 0	1.303	1.335	97.60	767	0.11	1
n40_Chain 0	0.649	0.682	95.16	1541	0.22	2

5250-5350 MHz:

Test Modes	Ton (ms)	Ton+off (ms)	Duty cycle (%)	1/T (Hz)	Duty cycle Factor (dB)	VBW Setting (kHz)
a_Chain 0	1.395	1.426	97.83	717	0.10	1
n20_Chain 0	1.303	1.335	97.60	767	0.11	1
n40_Chain 0	0.649	0.683	95.02	1541	0.22	2

5470-5725 MHz:

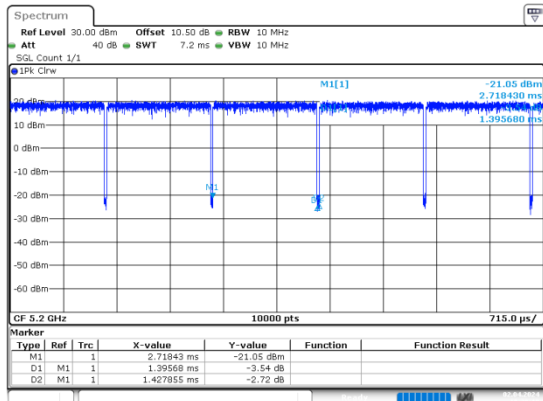
Test Modes	Ton (ms)	Ton+off (ms)	Duty cycle (%)	1/T (Hz)	Duty cycle Factor (dB)	VBW Setting (kHz)
a_Chain 0	1.394	1.428	97.62	717	0.10	1
n20_Chain 0	1.302	1.336	97.46	768	0.11	1
n40_Chain 0	0.649	0.683	95.02	1541	0.22	2

5725-5850 MHz:

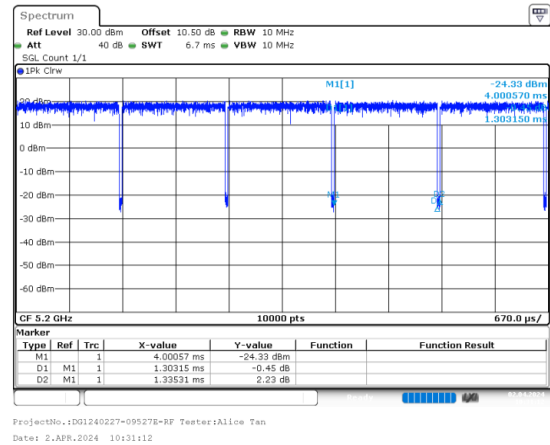
Test Modes	Ton (ms)	Ton+off (ms)	Duty cycle (%)	1/T (Hz)	Duty cycle Factor (dB)	VBW Setting (kHz)
a_Chain 0	1.306	1.336	97.75	766	0.10	1
n20_Chain 0	1.303	1.337	97.46	767	0.11	1
n40_Chain 0	0.649	0.683	95.02	1541	0.22	2

5150-5250 MHz:

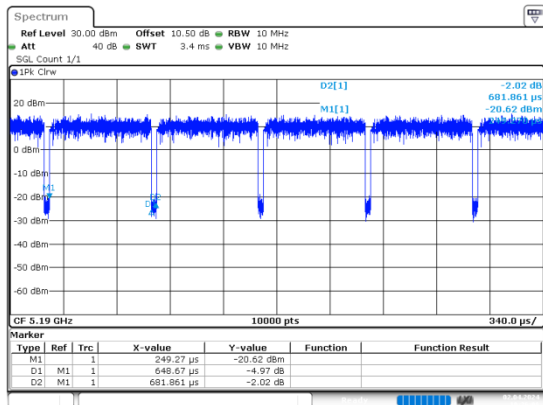
a_5200MHz_Chain 0



n20_5200MHz_Chain 0

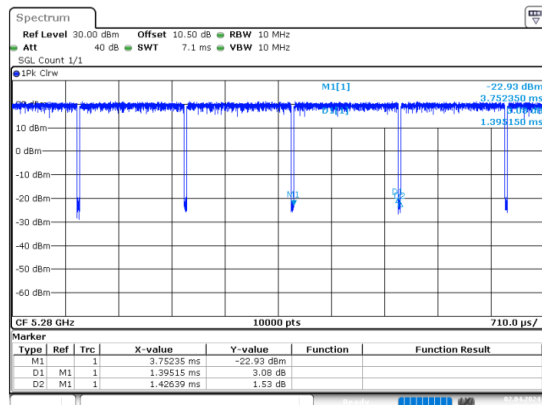


n40_5190MHz_Chain 0

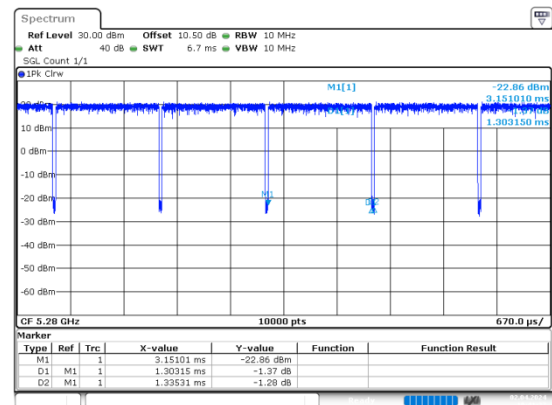


5250-5350 MHz:

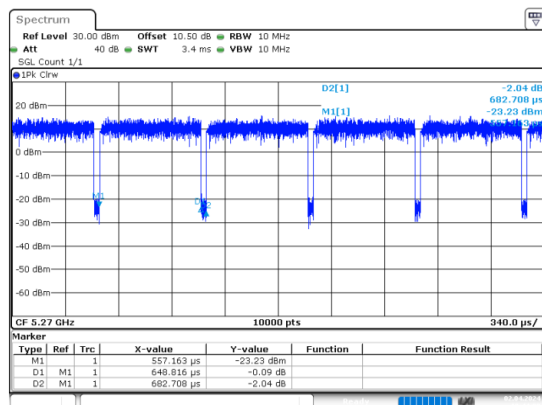
a_5280MHz_Chain 0



n20_5280MHz_Chain 0

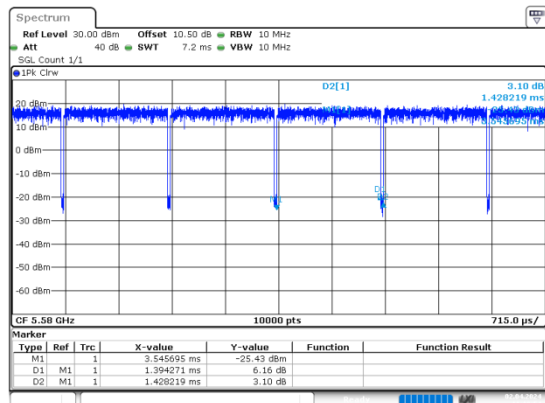


n40_5270MHz_Chain 0

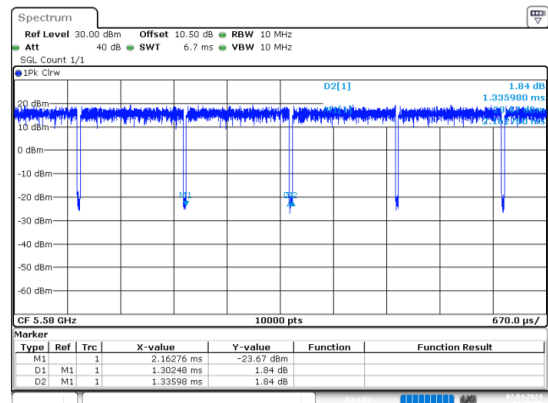


5470-5725 MHz:

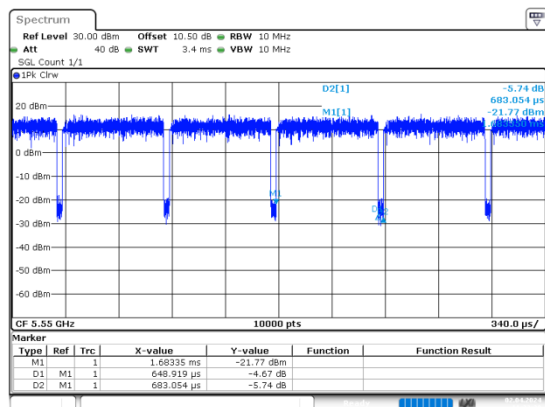
a_5580MHz_Chain 0



n20_5580MHz_Chain 0

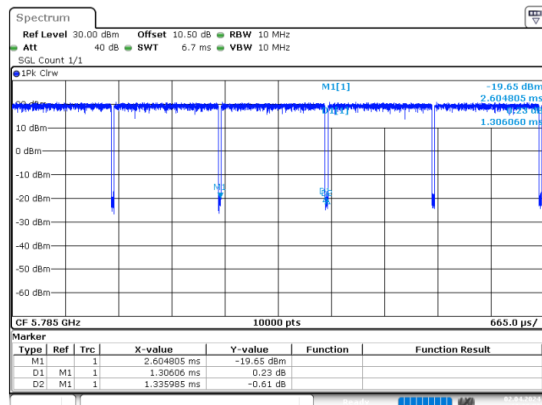


n40_5550MHz_Chain 0

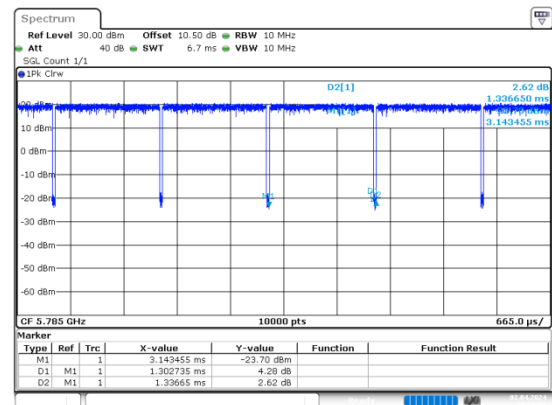


5725-5850 MHz:

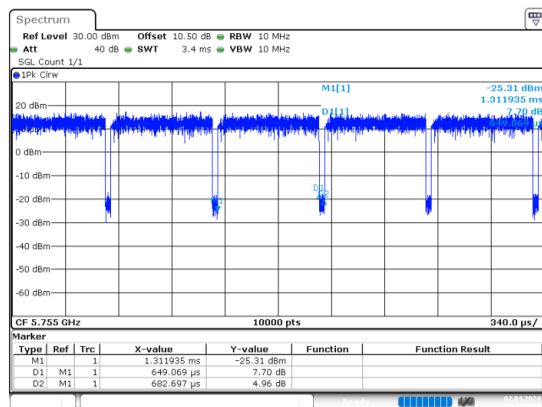
a_5785MHz_Chain 0



n20_5785MHz_Chain 0



n40_5755MHz_Chain 0



APPENDIX A - EUT PHOTOGRAPHS

Please refer to the attachment DG1240227-09527E-RF-EXP EUT EXTERNAL PHOTOGRAPHS and DG1240227-09527E-RF-INP EUT INTERNAL PHOTOGRAPHS.

APPENDIX B - TEST SETUP PHOTOGRAPHS

Please refer to the attachment DG1240227-09527E-RF-00D-TSP TEST SETUP PHOTOGRAPHS.

===== END OF REPORT =====